

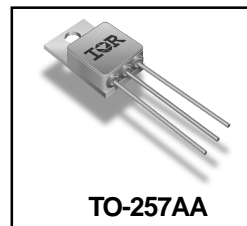
**POWER MOSFET
THRU-HOLE (TO-257AA)**

IRFY9130C,IRFY9130CM
100V, P-CHANNEL
HEXFET[®] MOSFET TECHNOLOGY

Product Summary

Part Number	R _{DS(on)}	I _D	Eyelets
IRFY9130C	0.3 Ω	-11.2A	Ceramic
IRFY9130CM	0.3 Ω	-11.2A	Ceramic

HEXFET[®] MOSFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry design achieves very low on-state resistance combined with high transconductance. HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits, and virtually any application where high reliability is required. The HEXFET transistor's totally isolated package eliminates the need for additional isolating material between the device and the heatsink. This improves thermal efficiency and reduces drain capacitance.



TO-257AA

Features:

- Simple Drive Requirements
- Ease of Paralleling
- Hermetically Sealed
- Electrically Isolated
- Ceramic Eyelets
- Ideally Suited For Space Level Applications

Absolute Maximum Ratings

	Parameter		Units
I _D @ V _{GS} = -10V, T _C = 25°C	Continuous Drain Current	-11.2	A
I _D @ V _{GS} = -10V, T _C = 100°C	Continuous Drain Current	-7.1	
I _{DM}	Pulsed Drain Current ①	-44	
P _D @ T _C = 25°C	Max. Power Dissipation	75	W
	Linear Derating Factor	0.6	W/°C
V _{GS}	Gate-to-Source Voltage	±20	V
E _{AS}	Single Pulse Avalanche Energy ②	400	mJ
I _{AR}	Avalanche Current ①	-11.2	A
E _{AR}	Repetitive Avalanche Energy ①	7.5	mJ
dv/dt	Peak Diode Recovery dv/dt ③	-5.5	V/ns
T _J	Operating Junction	-55 to 150	°C
T _{STG}	Storage Temperature Range		
	Lead Temperature	300(0.063in./1.6mm from case for 10 sec)	
	Weight	4.3 (Typical)	g

For footnotes refer to the last page

Electrical Characteristics @ T_j = 25°C (Unless Otherwise Specified)

Parameter	Min	Typ	Max	Units	Test Conditions
BV _{DSS}	-100	—	—	V	V _{GS} = 0V, I _D = -1.0mA
ΔBV _{DSS} /ΔT _J	—	-0.1	—	V/°C	Reference to 25°C, I _D = -1.0mA
R _{DS(on)}	—	—	0.30	Ω	V _{GS} = -10V, I _D = -7.1A ④
V _{GS(th)}	-2.0	—	-4.0	V	V _{DS} = V _{GS} , I _D = -250μA
g _{fs}	2.5	—	—	S (r)	V _{DS} > -15V, I _{DS} = -7.1A ④
I _{DSS}	—	—	-25	μA	V _{DS} = -80V, V _{GS} = 0V
	—	—	-250		V _{DS} = -80V, V _{GS} = 0V, T _J = 125°C
I _{GSS}	—	—	-100	nA	V _{GS} = -20V
I _{GSS}	—	—	100		V _{GS} = 20V
Q _g	—	—	30	nC	V _{GS} = -10V, I _D = -11.2A
Q _{gs}	—	—	7.1		V _{DS} = -50V
Q _{gd}	—	—	2.1		
t _{d(on)}	—	—	60	ns	V _{DD} = -50V, I _D = -11.2A, R _G = 7.5Ω
t _r	—	—	140		
t _{d(off)}	—	—	140		
t _f	—	—	140		
L _S + L _D	—	6.8	—	nH	Measured from drain lead (6mm/0.25in. from package) to source lead (6mm/0.25in. from package)
C _{iss}	—	800	—	pF	V _{GS} = 0V, V _{DS} = -25V f = 1.0MHz
C _{oss}	—	350	—		
C _{rss}	—	125	—		

Source-Drain Diode Ratings and Characteristics

Parameter	Min	Typ	Max	Units	Test Conditions
I _S	—	—	-11.2	A	
I _{SM}	—	—	-44		
V _{SD}	—	—	-4.7	V	T _j = 25°C, I _S = -11.2A, V _{GS} = 0V ④
t _{rr}	—	—	250	nS	T _j = 25°C, I _F = -11.2A, di/dt ≤ -100A/μs
Q _{RR}	—	—	3.0	μC	V _{DD} ≤ -50V ④
t _{on}	Forward Turn-On Time Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by L _S + L _D .				

Thermal Resistance

Parameter	Min	Typ	Max	Units	Test Conditions
R _{thJC}	—	—	1.67	°C/W	
R _{thCS}	—	0.21	—		
R _{thJA}	—	—	80		Typical socket mount

Note: Corresponding Spice and Saber models are available on the G&S Website.

For footnotes refer to the last page

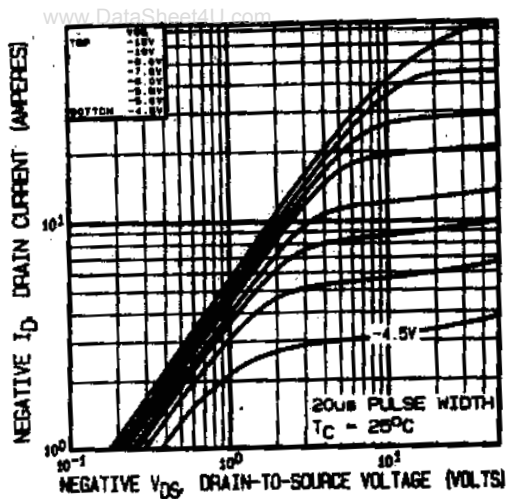


Fig 1. Typical Output Characteristics

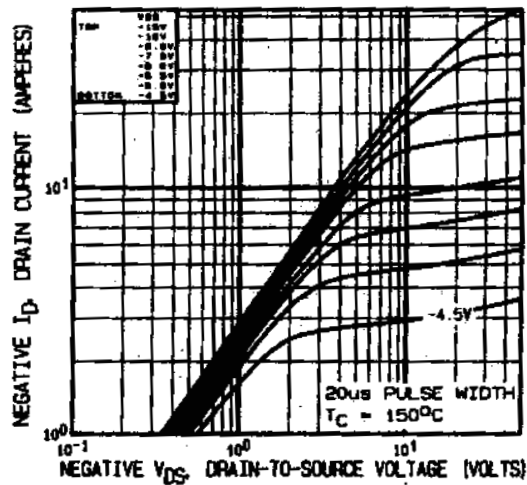


Fig 2. Typical Output Characteristics

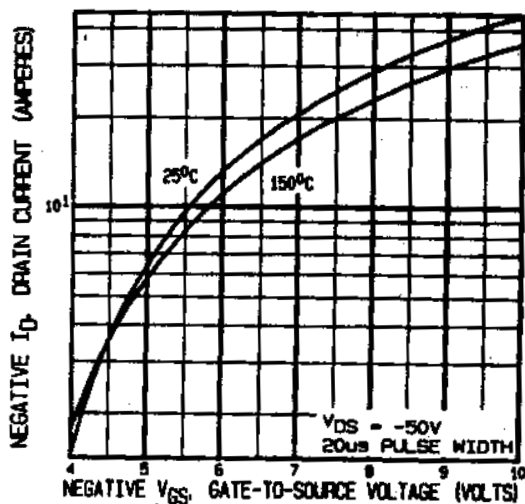


Fig 3. Typical Transfer Characteristics

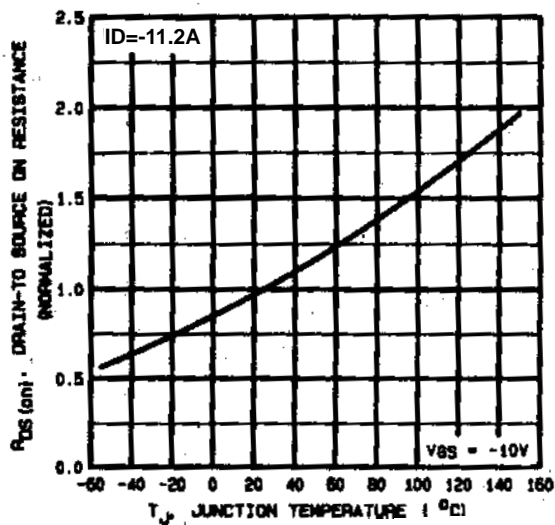


Fig 4. Normalized On-Resistance
Vs. Temperature

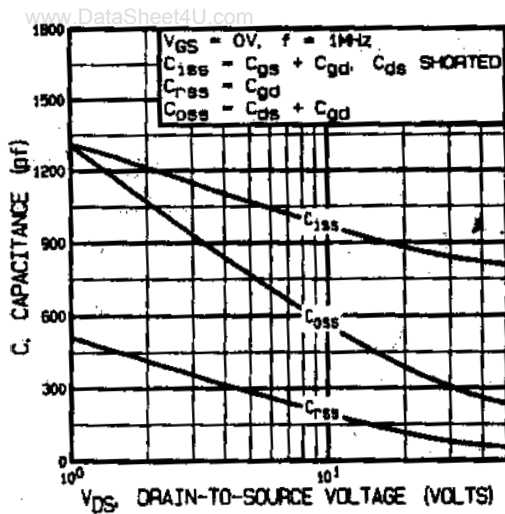


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

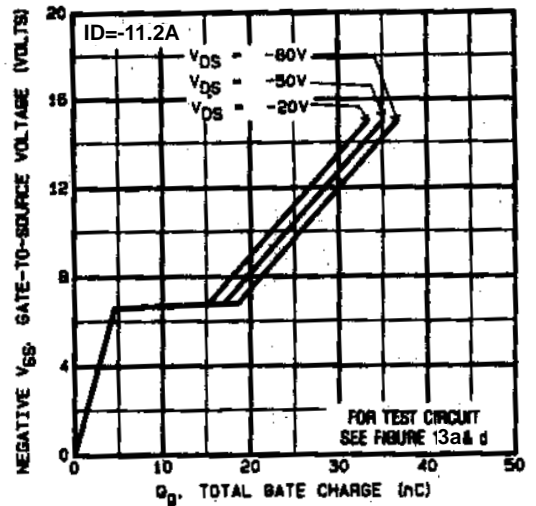


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

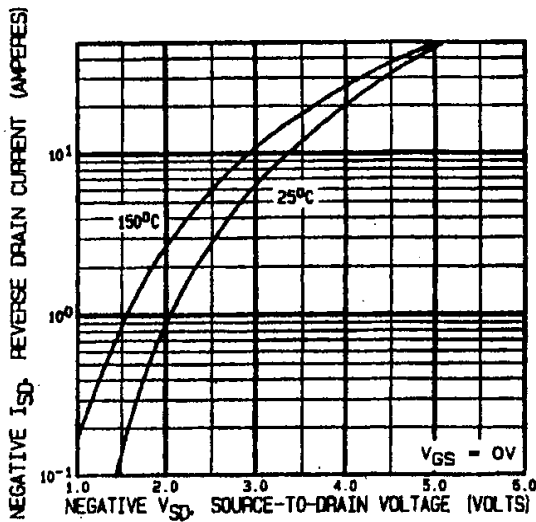


Fig 7. Typical Source-Drain Diode Forward Voltage

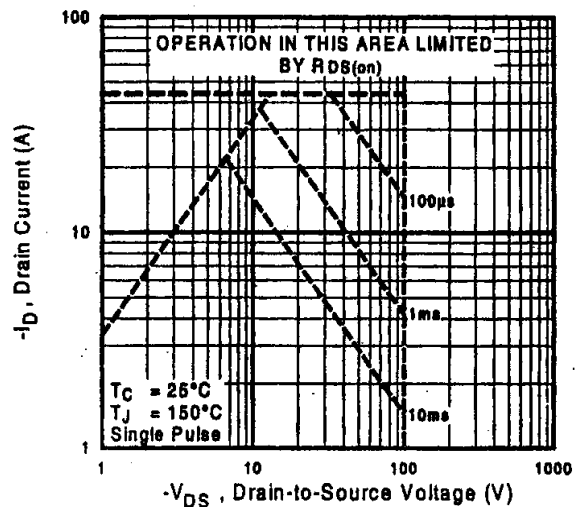


Fig 8. Maximum Safe Operating Area

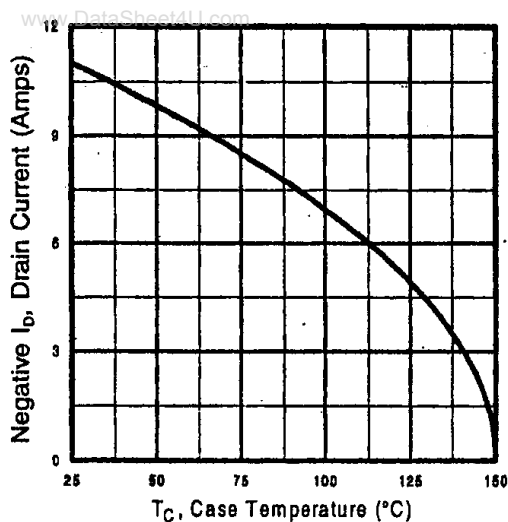


Fig 9. Maximum Drain Current Vs. Case Temperature

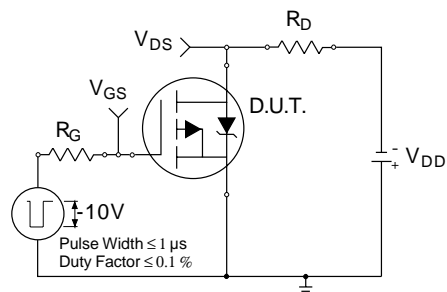


Fig 10a. Switching Time Test Circuit

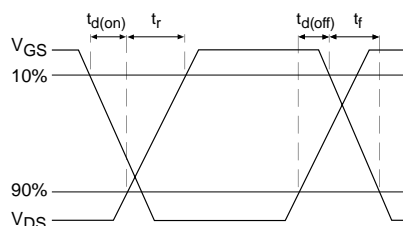


Fig 10b. Switching Time Waveforms

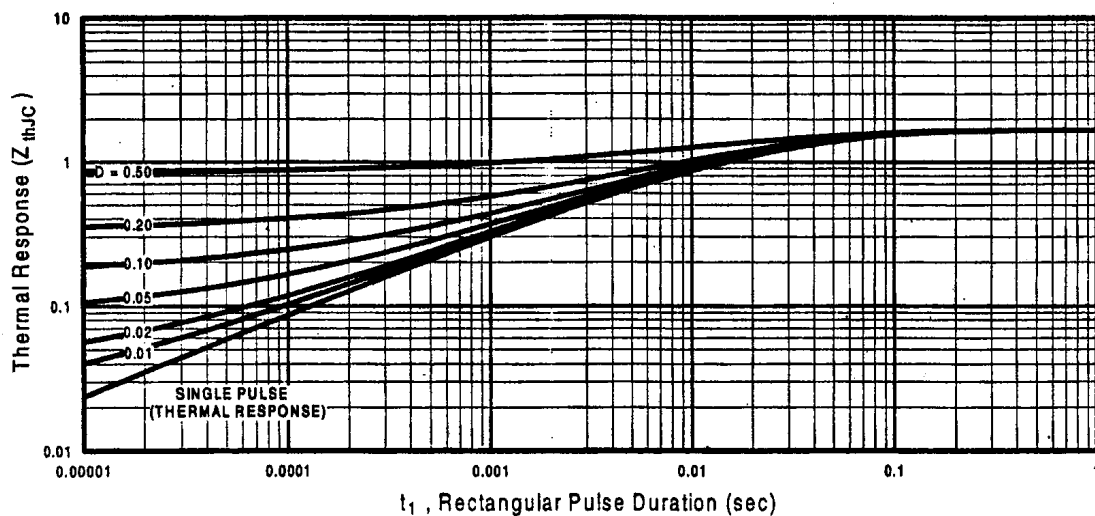


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

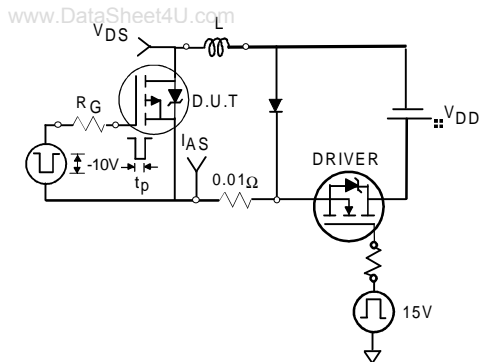


Fig 12a. Unclamped Inductive Test Circuit

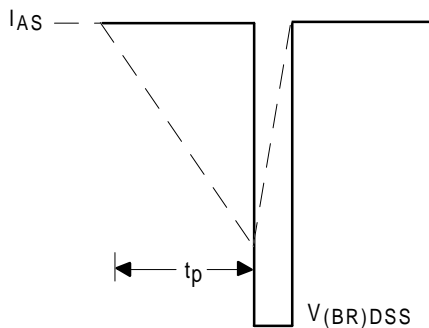


Fig 12b. Unclamped Inductive Waveforms

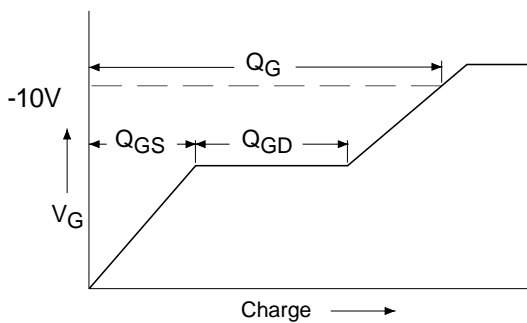


Fig 13a. Basic Gate Charge Waveform

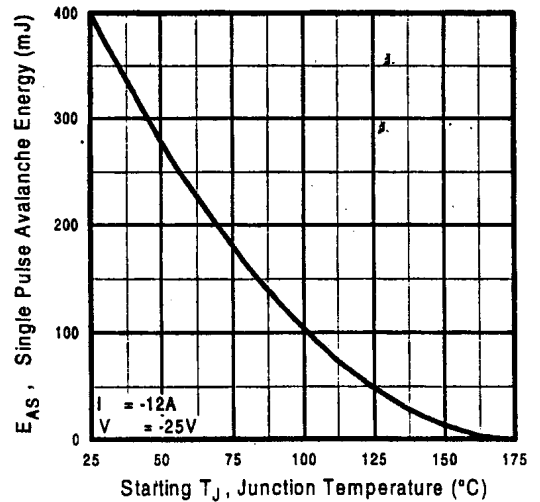


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

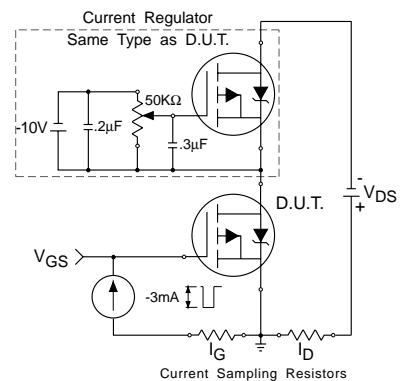
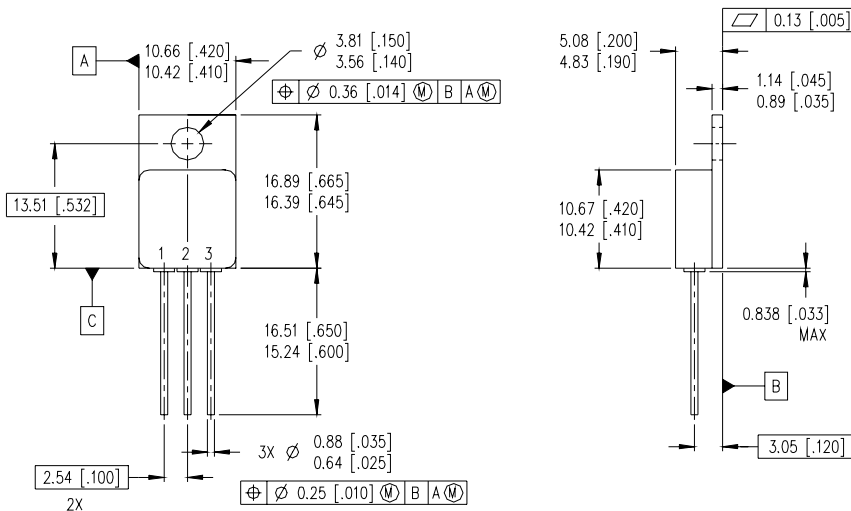


Fig 13b. Gate Charge Test Circuit

Foot Notes:

- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
- ② $V_{DD} = -25V$, starting $T_J = 25^\circ C$, $L = 6.4mH$
Peak $I_L = -11.2A$, $V_{GS} = -10V$
- ③ $I_{SD} \leq -11.2A$, $di/dt \leq -140A/\mu s$,
 $V_{DD} \leq -100V$, $T_J \leq 150^\circ C$
- ④ Pulse width $\leq 300 \mu s$; Duty Cycle $\leq 2\%$

Case Outline and Dimensions — TO-257AA



NOTES:

1. DIMENSIONING & TOLERANCING PER ANSI Y14.5M-1994.
2. CONTROLLING DIMENSION: INCH.
3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
4. OUTLINE CONFORMS TO JEDEC OUTLINE TO-257AA.

LEGEND

D - DRAIN
S - SOURCE
G - GATE

